

Supporting information

**Cryogenic abnormal thermal expansion property of carbon-doped
La(Fe,Si)₁₃ compounds**

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The variable-temperature X-ray diffraction spectra for samples of $\text{LaFe}_{11.5}\text{Si}_{1.5}\text{C}_x$ ($x=0, 0.2, 0.4$ and 0.6)

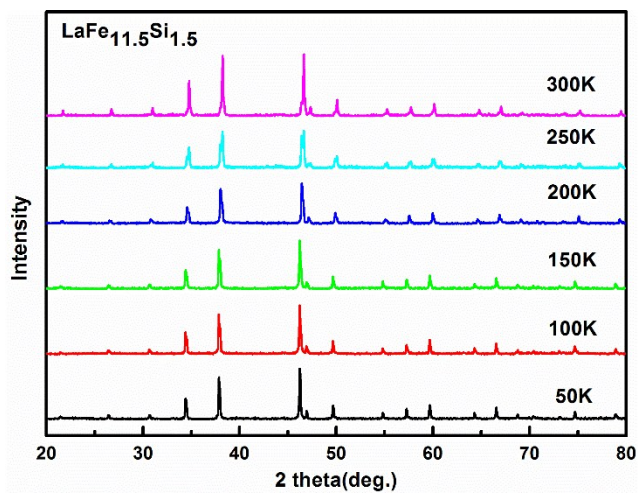


Fig. S1 The variable-temperature X-ray diffraction patterns from 50 to 300 K for sample of $\text{LaFe}_{11.5}\text{Si}_{1.5}$.

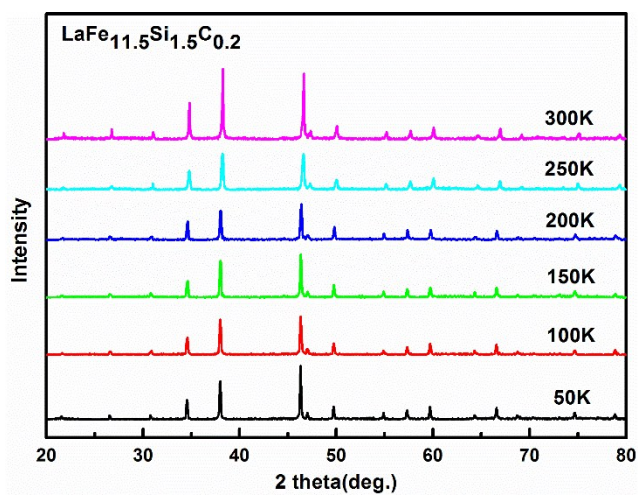


Fig. S2 The variable-temperature X-ray diffraction patterns from 50 to 300 K for sample of $\text{LaFe}_{11.5}\text{Si}_{1.5}\text{C}_{0.2}$.

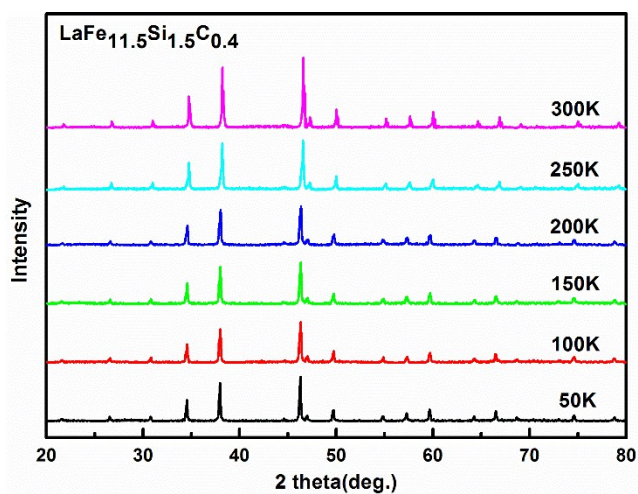


Fig. S3 The variable-temperature X-ray diffraction patterns from 50 to 300 K for sample of $\text{LaFe}_{11.5}\text{Si}_{1.5}\text{C}_{0.4}$.

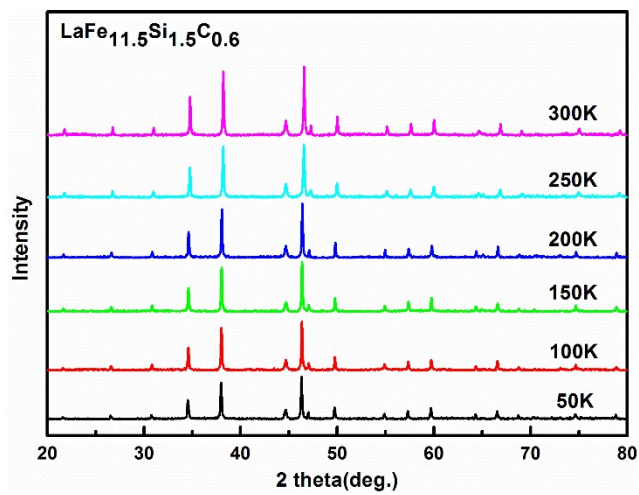


Fig. S4 The variable-temperature X-ray diffraction patterns from 50 to 300 K for sample of $\text{LaFe}_{11.5}\text{Si}_{1.5}\text{C}_{0.6}$.